

**Notice of References Cited**

Application/Control No.

09/986,637

Applicant(s)/Patent Under  
Reexamination  
CHEN ET AL.

Examiner

Stephen J. Kalafut

Art Unit

1745

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,628,010	12-1986	Iwanciow	429/19
	B	US-6,544,400	04-2003	Hockaday et al.	429/40 X
	C	US-6,592,741	07-2003	Nakanishi et al.	429/17 X
	D	US-2002/0182459	12-2002	Hockaday et al.	429/19
	E	US-2003/0014917	01-2003	Rusta-Sellehy et al.	48/61
	F	US-2003/0091876	05-2003	Rusta-Sellehy et al.	429/17
	G	US-2003/0091876	05-2003	Rusta-Sellehy et al.	429/20
	H	US-2003/0108832	06-2003	Lumsden et al.	431/2
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	WO 01/85606	11-2001	PCT	Zaluski et al.	C01B 3/06
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.